



Study and development of silicon carbide stray light optical components for third generation gravitational wave detectors

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Rudy Nahed, Olivier Dalverny, Antonino Chiummo, Marc Ferrato. Study and development of silicon carbide stray light optical components for third generation gravitational wave detectors. GWADW2016 – Impact of recent discoveries on future detector design, May 2016, Isola d’Elba, Italy. pp.0, 2016. hal-02487074

HAL Id: hal-02487074

<https://hal.science/hal-02487074>

Submitted on 21 Feb 2020

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Nahed, Rudy  and Dalverny, Olivier  and Chiummo, Antonino and Ferrato, Marc *Study and development of silicon carbide stray light optical components for third generation gravitational wave detectors*. In: GWADW2016 – Impact of recent discoveries on future detector design, 22 May 2016 - 28 May 2016 (Isola d'Elba, Italy). (Unpublished)

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Problematic and research objectives

Problematic

Stray light is the light that does not follow the intended path reaching the detector [1]. Subsequently, stray light was considered as an issue because scattered light from surfaces other than the mirrors surface, such as the walls of the cavity, will carry information about the displacement of the wall that will recouple back with the main beam adding a stray light field to the unperturbed field inside the interferometer:

$$E_{total} = E_{in} + E_s = E_{in} + \sqrt{f_{sc}} E_{out} e^{i\phi_s(t)} \quad E_{total} = E_{in} \exp \left[\sqrt{f_{sc}} \frac{P_{out}}{P_{in}} (\cos \phi_s(t) + i \sin \phi_s(t)) \right]$$

This final profile of the equation contains a real part and an imaginary part. In this sense, the real part represents the amplitude modulation induced $\frac{dP(t)}{P}$ and the imaginary part represents the phase modulation $n_\phi(t)$ [1]:

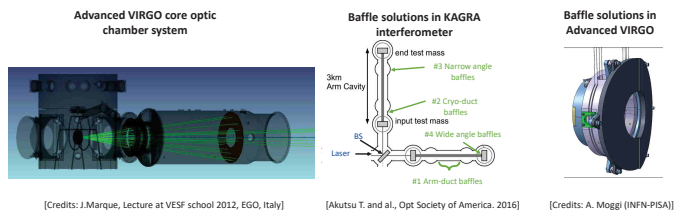
$$\frac{dP(t)}{P} = \sqrt{f_{sc}} \frac{P_{out}}{P_{in}} \cos \phi_s(t) \quad n_\phi(t) = \sqrt{f_{sc}} \frac{P_{out}}{P_{in}} \sin \phi_s(t)$$

Where E_s is the stray light field, E_{out} is the output field and ϕ_s is the phase angle that carries information about the scattered light.

Stray light in the current detectors is being reduced using light shades called « baffles ». In fact, the third generation detector will be using a very high power laser and the test masses will be subjected to the current baffles and that can bear these conditions. Hence, we had to find a new material that can be a replacement for the current baffles and that can bear these conditions.

[1] Camuel B., and al., Opt. Express. 2013 May 6; 21(9):10546-62

The chamber and the core optics with stray light



Research objectives

- Studying and analysing the thermal and mechanical behavior of SiC under interferometer conditions
- Studying the possibility of stray light reduction or elimination by using SiC as baffles

Methodology

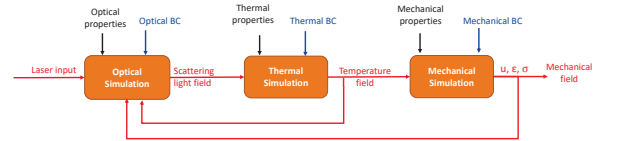
Multiple actions combining

- Optical characterization of the most promising materials (SiC, coated SiC...),
- Analysis of the thermal and thermomechanical changes induced by scattering light flux,
- Analysis of the influence of this changes on the scattering light process (if needed).

All the methodology could be applied to advanced virgo and/or third generation interferometer.

Key points : cryogenic temperature, high laser power density

Methodology of simulation



Optical Work

Optical work

- Material Requirement (SiC is a very promising candidate)
- Optical Characterization
 - Measuring the scattering at room temperature (Advanced VIRGO) and at cryogenic temperature (Einstein Telescope ET)
 - Same conditions for measuring the reflectivity of SiC

	Candidate			
Requirements	SS 304	Al-NiPW	SiC-CVD	SiC
Low Scattering	*(RT)	**	***	*
High Laser Induced Damage Threshold LIDT	*(RT)	**	***	***
High Thermal Conductivity	*	***	***	***
Low Thermal Expansion	**	*	***	***
High Stiffness	**	*	***	***
High Absorption Coefficient	*	***	***	**

*** Most promising candidate

Physical characterization of BOOSTEC® SiC

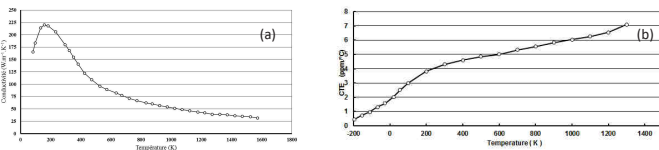


Fig: BOOSTEC® SiC experimental data as a function of the temperature, (a) thermal conductivity, (b) thermal expansion.

Optical characterization of 3 samples of MERSEN SiC

- TIS is calculated as the ratio between scattered output light and input light source
- TIS measured as a function of the root mean square roughness

$$TIS^* = \frac{P_{out}}{P_{in}}$$

$$TIS^{**} = 1 - \exp \left[- \left(\frac{4\pi \cos \theta_i \sigma}{\lambda} \right)^2 \right]$$

[Bennett and Porteus]

λ is the wavelength of the laser
 σ is the surface roughness of the sample
 θ_i is the incident angle ($2^\circ - 3^\circ$)

Polished Sample	Process	Surface Roughness (nm)	TIS** (ppm)	TIS* (ppm)	Reflectivity at Brewster angle(%)	Reflectivity at 3 deg (%)
HIP BOOSTEC® SiC	Hot Isostatic Pressing	5	3487	2120	0.2	21
BOOSTEC® SiC polished (no HIP)	Pressureless sintering	2	558	4360	0.2	19
MERSEN SiC-CVD	Chemical Vapor Deposition	< 1	<<<	50	0.1	19

[V. Bavigadde, and A. Magazzu, EGO, Cascina (Italy)]

Conclusion & Next Steps

Conclusion

- BOOSTEC® SiC could be a good candidate for baffles for the third generation gravitational wave detectors regarding its thermal and mechanical properties.
- MERSEN SiC-CVD is a very promising material for this purpose due to its agreement with the optical requirements desired.
- Preliminary results of FE modeling interaction between the test mass and the baffle allowing us to study and analyze their temperature variation.

Next Steps

- Studying the characterization process of BOOSTEC® SiC under cryogenic temperature to explore whether the optical requirements are achieved.
- FE Studies of the thermal analysis of the conduction process.
- Mechanical analysis under room and cryogenic temperature of SiC setup must be explored to evaluate displacement, stress; strain and analyze mechanical behavior.
- Evaluating the possibility of using different types of coatings with the same substrate SiC.